## EXPRESS MAIL NO.: EV 415954305 US IN THE U.S. PATENT AND TRADEMARK OFFICE

In re U.S. Patent Application of:

APPLICANT:

Xiao, et al.

**SERIAL NO.:** 

Not yet assigned

FILING DATE:

Herewith

EXAMINER:

Not yet assigned Not yet assigned

ART UNIT: DOCKET NO.:

904.0101.U2(US)

TITLE:

REDUCTION OF NOISE, AND OPTIMIZATION OF

MAGNETIC FIELD SENSITIVITY AND ELECTRICAL

PROPERTIES IN MAGNETIC TUNNEL JUNCTION DEVICES

MAIL STOP: PATENT APPLICATION

Commissioner for Patents

P.O. Box 1450

Alexandria, VA 22313-1450

## **INFORMATION DISCLOSURE STATEMENT (37 C.F.R. 1.98(d))**

Dear Sir:

Pursuant to Sections 609 and 707.05(b) of the MPEP and 37 CFR 1.97-1.99, this IDS makes of record the prior art that was cited in the parent application S.N. 10/105,831, filed on March 25, 2002, which is relied on for an earlier filing date by the present patent application. The attached pages of PTO-1449 list the prior art from the parent application and other references. Since this application relies on the parent application for an earlier filing date, copies of the references cited in that parent application are not enclosed (37 C.F.R. 1.98(d)). However, if for any reason these references are not be found in the file jacket of the parent application, the Examiner is respectfully requested to contact the undersigned attorney, who will gladly provide copies of any missing references.

The citation of these documents should not be construed as a representation that a thorough search has been made, or that other, more pertinent material is not available.

Respectfully submitted,

Gerald J. Stanton

Reg. No. 46,008

April 14, 2004

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Page No.: 1 of: 2

## INFORMATION DISCLOSURE CITATION FORM FOR PATENT APPLICATION (FORM PTO-1449)

Docket No.: 904.0101.U2(US)

Serial No.

Applicant(s): Xiao et al.

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Docket No.: 904.0101.U2(US)

Serial No.:

(FORM PTO-1449)

Applicant(s): XIAO et al.

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Examine	r's Signature:	Date Considered:							
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	Include a copy of thi	s citation form with you	ir next corresponde	nce to the Applicant(s).					